


<b>Search Notes</b>  	<b>Application/Control No.</b>  10733264	<b>Applicant(s)/Patent Under Reexamination</b>  HOSHUYAMA, HIDEO
	<b>Examiner</b>  Tsai, Tsung-Yin	<b>Art Unit</b>  2609

SEARCHED			
Class	Subclass	Date	Examiner
382	254 with text	10/29/2010	TYT

SEARCH NOTES		
Search Notes	Date	Examiner
IEEE	3/12/2010	TYT
IDS and Given english NPL	3/12/2010	TYT
Inventor Search on eDan	3/12/2010	TYT
Google Patent	3/12/2010	TYT
Google Scholar with inventor and keyword search	3/12/2010	TYT
US-PGPUB, USPAT, USOCR, FPRS, EPO, JPO, DERWENT, IBM_TDB	3/12/2010	TYT
Classification Search	3/12/2010	TYT
forward and backward citation	3/12/2010	TYT
Review and Update search above	10/29/2010	TYT
Andrew Johns (Primary 2624): Consult: using new and better reference with RCE. Result: Always provide new or even better reference when possible especially with new non-final office action.	10/29/2010	TYT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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